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(54) AUTOMATIC TESTING METHOD CORRESPONDING TO DATA TYPE

(57)Abstract:

PURPOSE: To make it possible to prepare test data only by applying program specification by previously storing typical test data to be used for a test for the data of a certain data type correspondingly to the definition of the data type.

CONSTITUTION: A test level for specifying the level of a detailed test is stored in accordance with an operator's instruction. According as the test level is increased, the number of test data to be prepared is increased and more detailed tests can be executed. Then, program specification to be tested is stored. Information relating to an argument to be given to a program to be tested is acquired by one argument from the program specification, and test data corresponding to the information of the argument are prepared by using standard test data 11 or program parts 13. Then, the previously stored test level is compared with the test level of the obtained test data, only the test data whose test level is lower than T is fetched and outputted together with the information of the argument.
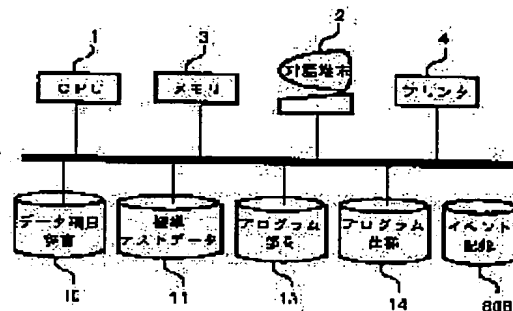
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